

**THE FOLLOWING ARE THE ENGLISH TRANSLATION
OF ANNEXES TO THE INTERNATIONAL PRELIMINARY
EXAMINATION REPORT (ARTICLE 34):**

Amended Specification (Pages 85 and 85/1)

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CLAIMS

[1] (Amended) An anisotropically conductive connector suitably used for, in a wafer inspection apparatus for performing electrical inspection of a great number of integrated circuits formed on a wafer, which comprises: a circuit board for inspection having a great number of inspection electrodes on a front surface thereof; and a probe card having a circuit board for connection, on the back surface of which a plurality of terminal electrodes have been formed in accordance with a pattern corresponding to a pattern of the inspection electrodes of the circuit board for inspection, and a contact member, which is provided on the front surface of the circuit board for connection, and on which a great number of contacts brought into contact with respective electrodes to be inspected of the integrated circuits on the wafer, which is an object of inspection, have been arranged, and arranged in such a manner that the terminal electrodes of the circuit board for connection are opposed to their corresponding inspection electrodes of the circuit board for inspection, electrically connecting the inspection electrodes to the respective terminal electrodes by being arranged between the circuit board for inspection and the circuit board for connection in the probe card, and the anisotropically conductive connector comprises an elastic anisotropically conductive film composed of a

plurality of conductive parts for connection each extending in a thickness-wise direction of the film and arranged in a state separated from each other along a plane direction of the film and an insulating part formed among these

5 conductive parts for connection, and a frame plate for supporting the elastic anisotropically conductive film, wherein

the frame plate is formed of a metallic material having a coefficient of linear thermal expansion of 3×10^{-6} to $2 \times 10^{-5} \text{ K}^{-1}$, the conductive parts for connection in

10 the elastic anisotropically conductive film are obtained by filling conductive particles having a number average particle diameter of 20 to 80 μm and exhibiting magnetism in an elastic polymeric substance at a high density, the

15 conductive particles have, on a surface of which, a coating layer composed of a noble metal and having a thickness of at least 20 nm, each of the conductive parts for connection has a durometer hardness of 10 to 35, and an electric resistance between conductive parts for connection

20 adjoining each other is at least 10 $\text{M}\Omega$.

[2] The anisotropically conductive connector according to claim 1, wherein the frame plate has at least one through-hole extending in the thickness-wise direction,